

Electrical Performance

Parameter	Min.	Typ.	Max.	Units	Notes
Output Frequency	1		800	MHz	As specified
Supply Voltage	2.97	3.3	3.63	V	
Supply Current			25	mA	<24 MHz
			65	mA	24 to 96 MHz
			100	mA	96 to 800 MHz
Frequency Stability			±20 to ±50	ppm	See Note 1 below
Operating Temp. Range	-40		+85	°C	As specified
Output Logic 0, V _{OL}			V _{CC} - 1.620	V	-40 to +85°C
Output Logic 1, V _{OH}	V _{CC} - 1.025			V	-40 to +85°C
Output Load	50Ω to V _{CC} - 2V				output requires termination
Duty Cycle	45		55	%	measured at V _{DD} - 1.3 VDC
Rise and Fall Time		0.5	1.5	ns	measured 20/80% of waveform
Jitter, Phase		2.5	4	ps RMS (1-σ)	12kHz to 20MHz frequency band
Jitter, Accumulated			6	ps RMS (1-σ)	10,000 adjacent periods
Jitter, Total			40	ps pk-pk	10,000 random periods
Phase Noise		-90		dBc/Hz	100 Hz offset (155.52 MHz output)
		-115		dBc/Hz	1 kHz offset (155.52 MHz output)
		-125		dBc/Hz	10 kHz offset (155.52 MHz output)
		-119		dBc/Hz	100 kHz offset (155.52 MHz output)

Notes:

- As specified. Stability includes all combinations of operating temperature, load changes, rated input (supply) voltage changes, initial calibration tolerance (25°C), aging (5 years at 40°C average effective ambient temperature), shock and vibration.
- For specifications other than those listed, please contact sales

Output Enable / Disable Function (Active High Default and Active Low*)

Parameter	Min.	Typ.	Max.	Units	Notes
Input Voltage (pin OE), Output Enable	V _{OH}			V	or open (Legacy SEL3813 and SEL3814)
Input voltage (pin OE), Output Disable			V _{OL}	V	Outputs disabled to Hi-Z
*Input Voltage (OE pin), Output Enable			V _{OL}	V	or open (Legacy SEL3811 and SEL3812)
*Input voltage (OE pin), Output Disable	V _{OH}			V	Outputs disabled to Hi-Z

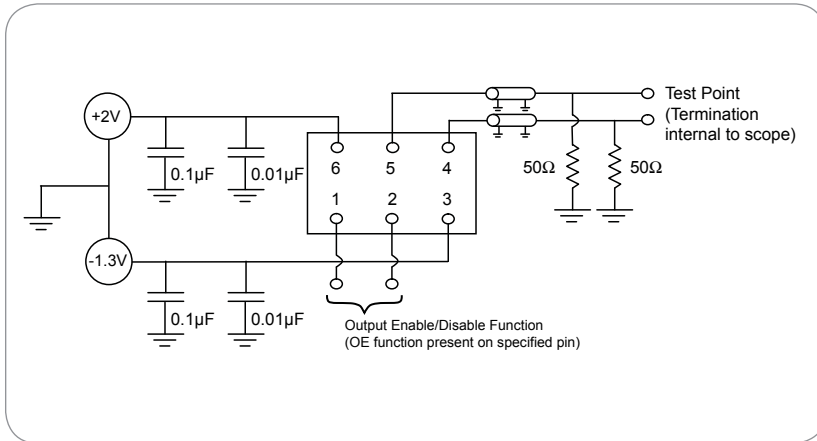
*Note:

- Oe active low option is available. Please contact sales.

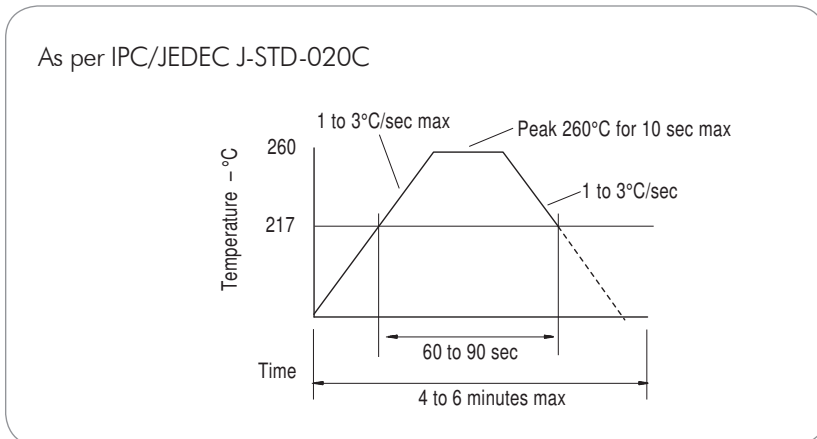
Absolute Maximum Ratings

Parameter	Min.	Typ.	Max.	Units	Notes
Storage Temperature	-55		+125	°C	

Test Circuit



Reflow Soldering Profile



Reliability Test Ratings

This product is rated to meet the following test conditions:

Type	Parameter	Test Condition
Mechanical	Shock	MIL-STD-883, Method 2002, Condition B
Mechanical	Solderability	JESD22-B102-D Method 2 (Preconditioning E)
Mechanical	Terminal strength	MIL-STD-883, Method 2004, Condition D
Mechanical	Gross leak	MIL-STD-883, Method 1014, Condition C
Mechanical	Fine leak	MIL-STD-883, Method 1014, Condition A2 ($R_1 = 2 \times 10^{-8}$ atm cc/s)
Mechanical	Solvent resistance	MIL-STD-202, Method 215
Environmental	Thermal shock	MIL-STD-883, Method 1011, Condition A
Environmental	Moisture resistance	MIL-STD-883, Method 1004
Environmental	Vibration	MIL-STD-883, Method 2007, Condition A
Environmental	Resistance to soldering heat	J-STD-020C Table 5-2 Pb-free devices (2 cycles max)

Output Waveform

